



AGH UNIVERSITY OF SCIENCE AND TECHNOLOGY  
IM. STANISŁAWA STASZICA W KRAKOWIE  
Faculty of Computer Science, Electronics and Telecommunications  
DEPARTMENT OF ELECTRONICS



# ELECTRONIC DEVICES

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## AMPLIFYING ELEMENTS



**JUNCTION FIELD EFFECT TRANSISTOR - JFET**

**METAL-OXIDE-SEMICONDUCTOR  
FIELD EFFECT TRANSISTOR - MOSFET**

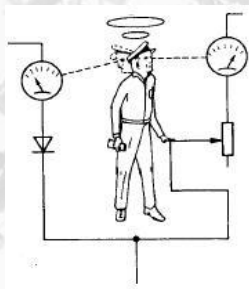
**BIPOLAR JUNCTION TRANSISTOR - BJT**



## PRINCIPLE OF SIGNALS AMPLIFICATION

Transistors are electronic devices that fulfil many different functions, but amplification of signals is their main feature

In amplifier circuits transistors convert weak signals into higher power ones



„transistor man”

Paul Horowitz *Sztuka Elektroniki*

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## JUNCTION FIELD EFFECT TRANSISTOR JFET

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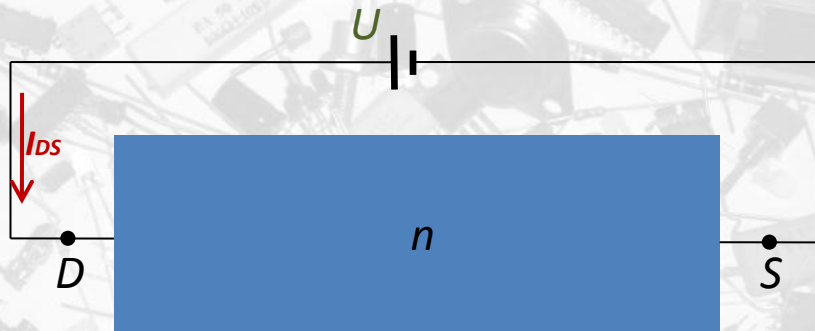
Electronic devices – JFETs

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# JUNCTION FIELD EFFECT TRANSISTOR

## BASICS OF OPERATION



At  $U = \text{const.}$ : how can we change current  $I_D$ ?

In JFET transistors, the majority carriers drift current is controlled by an applied external electric field

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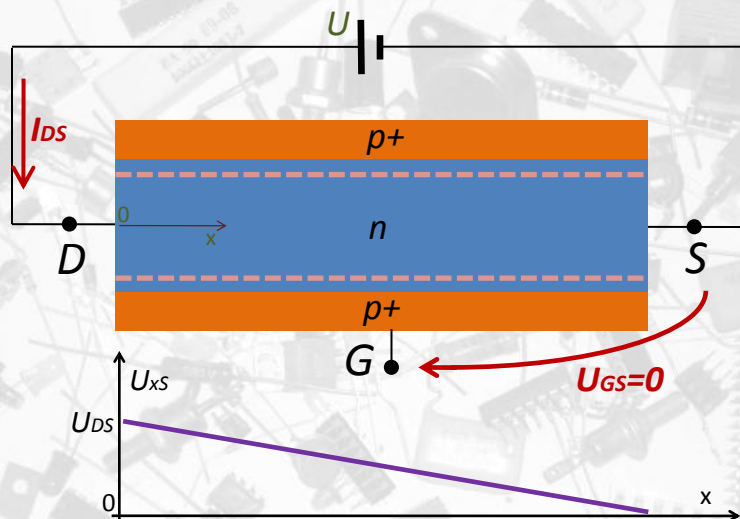
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# JUNCTION FIELD EFFECT TRANSISTOR

## BASICS OF OPERATION



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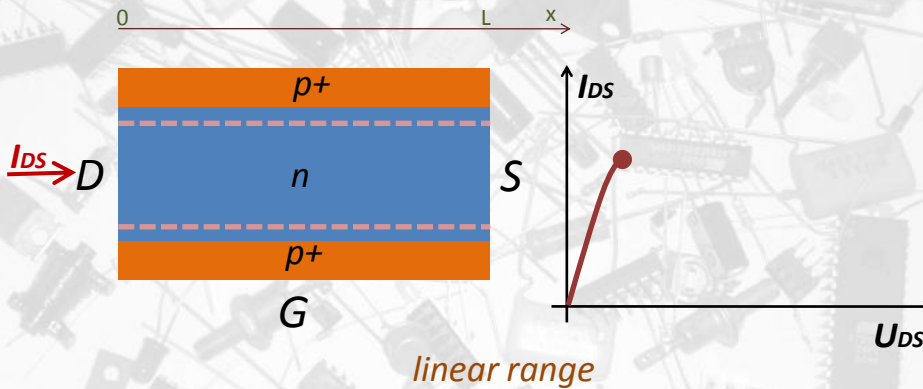


# JUNCTION FIELD EFFECT TRANSISTOR

## BASICS OF OPERATION



The shape of the depletion layer in the channel of junction field effect transistor at zero biased gate



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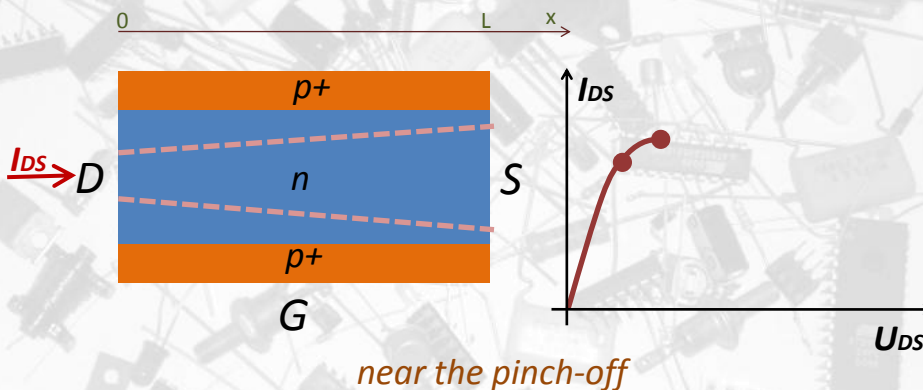


# JUNCTION FIELD EFFECT TRANSISTOR

## BASICS OF OPERATION



The shape of the depletion layer in the channel of junction field effect transistor at zero biased gate



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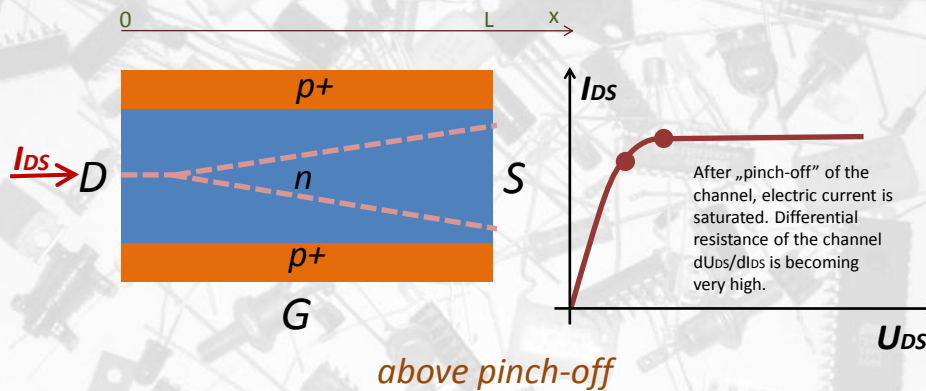
Electronic devices – JFETs

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# JUNCTION FIELD EFFECT TRANSISTOR

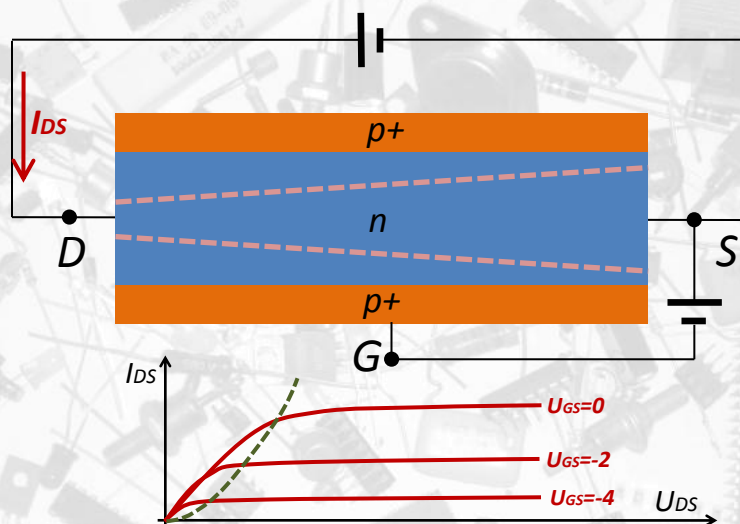
## BASICS OF OPERATION

The shape of the depletion layer in the channel of junction field effect transistor at zero biased gate



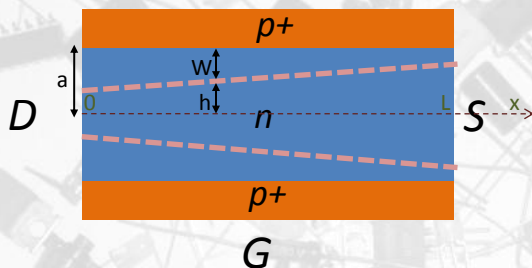
# JUNCTION FIELD EFFECT TRANSISTOR

## INFLUENCE OF REVERSE BIASED GATE



# JUNCTION FIELD EFFECT TRANSISTOR

## DETERMINATION OF THRESHOLD VOLTAGE



we estimate the width of the depletion layer at  $x=0$ , (due to dopant concentration we assume that depletion area spreads mainly in the direction n-channel):

$$W(x=0) = \left[ \frac{2\epsilon U_{GD}}{qN_D} \right]^{\frac{1}{2}}$$

Clamping of the channel (pinch-off) at the drain occurs when :

$$h(x=0) = a - W(x=0) = 0$$

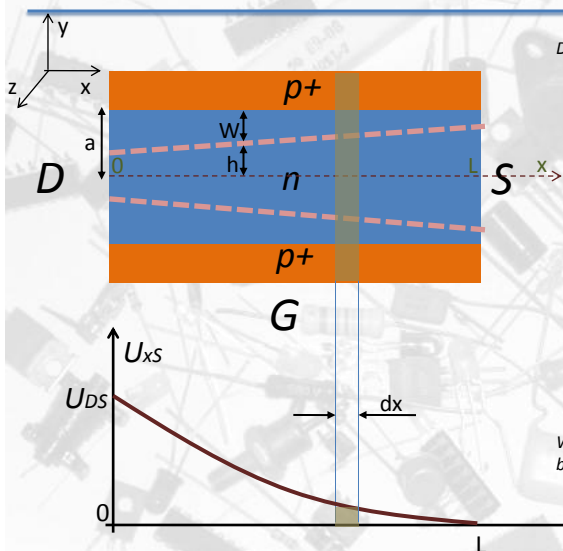
Therefore,  $W(x=0) = a$ . If you define a threshold voltage  $U_p$ , as a voltage  $U_{GD}$  at the clamping of channel, then:

$$\left[ \frac{2\epsilon U_p}{qN_D} \right]^{\frac{1}{2}} = a$$

$$U_p = \frac{qa^2 N_D}{2\epsilon}$$

# JUNCTION FIELD EFFECT TRANSISTOR

## DETERMINATION OF DRAIN CURRENT



Differential volume unit of the neutral channel part:

$$Z2h(x)dx$$

Resistance of the volume unit :

$$\frac{\rho dx}{Z2h(x)}$$

( $\rho$  - resistivity of channel,  $Z$  - thickness of channel)

Current  $I_{DS}$  does not change along the channel and it is associated with a differential voltage drop  $dU_{xS}$  at the elementary resistive volume unit:

$$I_{DS} = - \frac{Z2h(x)}{\rho} \frac{dU_{xS}}{dx}$$

Width  $h(x)$  at point  $x$  depends on the local reverse bias polarization of gate and channel  $-U_{Gx}$



# JUNCTION FIELD EFFECT TRANSISTOR

## DETERMINATION OF DRAIN CURRENT



Width  $h(x)$  at  $x$  depends on locally reverse polarized gate and the channel  $-U_{GS}$

$$h(x) = a - W(x) = a - \left[ \frac{2\epsilon(-U_{GS})}{qN_D} \right]^{\frac{1}{2}} = a \left[ 1 - \left( \frac{U_{GS} - U_{GS}}{U_P} \right)^{\frac{1}{2}} \right]$$

We take into account that:  $U_{GS} = U_{GS} - U_{SS}$   $U_P = \frac{qa^2 N_D}{2\epsilon}$

After introduction to the equation describing  $I_{DS}$ , we get:

$$\frac{2Za}{\rho} \left[ 1 - \left( \frac{U_{GS} - U_{GS}}{U_P} \right)^{\frac{1}{2}} \right] dU_{GS} = -I_{DS} dx$$

After integration we obtain:

$$I_{DS} = G_0 U_P \left[ \frac{U_{DS}}{U_P} + \frac{2}{3} \left( -\frac{U_{GS}}{U_P} \right)^{\frac{3}{2}} - \frac{2}{3} \left( \frac{U_{DS} - U_{GS}}{U_P} \right)^{\frac{3}{2}} \right]$$

where  $G_0 = \frac{2aZ}{\rho L}$  is the channel conductance

The above equation is valid until channel „pinch-off”, when  $U_{DS} - U_{GS} = U_P$

*Derivations were based on: „Przyrządy półprzewodnikowe”, Ben G. Streetman*



# JUNCTION FIELD EFFECT TRANSISTOR

## DETERMINATION OF DRAIN CURRENT



Assuming that the saturation current remains the same as that one at the channel „pinch-off”, we get:

$$I_{DSS} = G_0 U_P \left[ \frac{U_{GS}}{U_P} + \frac{2}{3} \left( -\frac{U_{GS}}{U_P} \right)^{\frac{3}{2}} + \frac{1}{3} \right]$$

For low voltages  $U_{DS} < U_{GS} - U_P$ , drain current linearly depends on the  $U_{GS}$  (linear operation range):

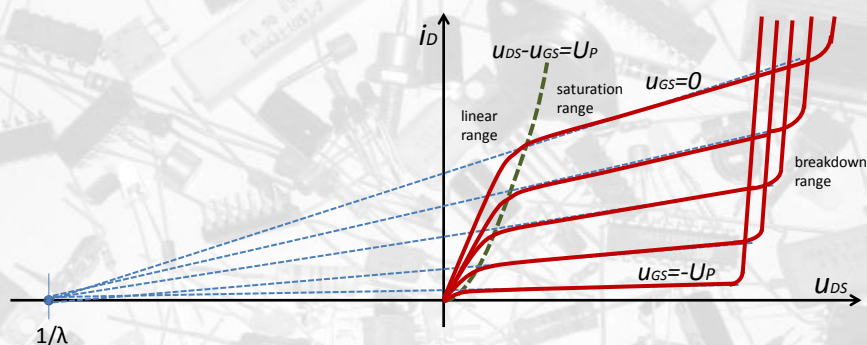
$$I_D = G_0 \left( 1 - \sqrt{\frac{U_{GS}}{U_P}} \right) U_{DS}$$

For voltages:  $U_{DS} > U_{GS} - U_P$ , transistor works „in saturation”:

$$I_D = I_{DSS} \left( 1 - \frac{U_{GS}}{U_P} \right)^2$$

# JUNCTION FIELD EFFECT TRANSISTOR

## REAL CHARACTERISTICS OF DRAIN CURRENT



$$I_D = I_{DSS} \left( 1 - \frac{u_{GS}}{U_P} \right)^2 (1 + \lambda u_{DS})$$

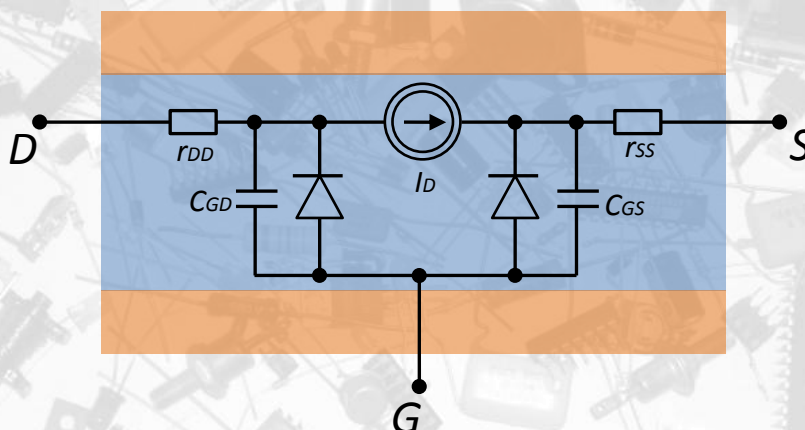
- the drain current in the saturation range, taking into account shortening of the channel

$\lambda$  - channel length modulation factor :

it describes the reduction of the channel under the influence of the voltage  $U_{DS}$  and increasing  $I_D$  current

# JUNCTION FIELD EFFECT TRANSISTOR

## LARGE-SIGNAL MODEL



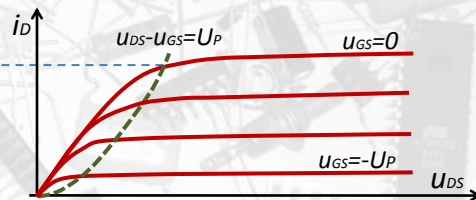
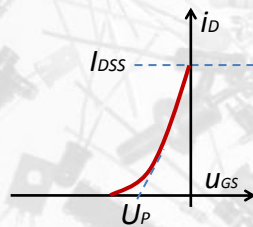
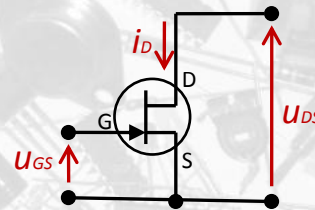
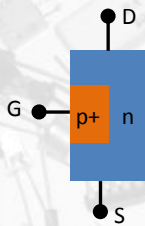


# JUNCTION FIELD EFFECT TRANSISTOR



## N-CHANNEL

### N-channel FET



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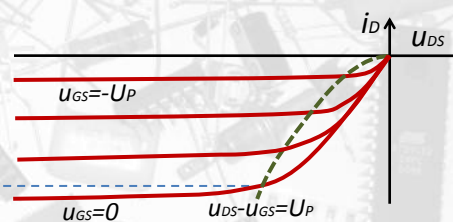
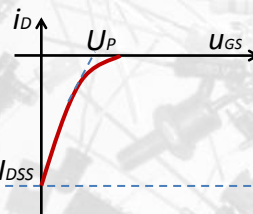
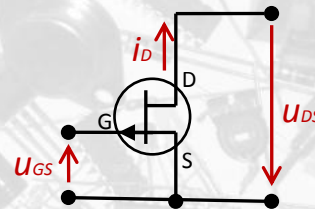
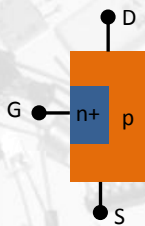


# JUNCTION FIELD EFFECT TRANSISTOR



## P-CHANNEL

### P-channel FET



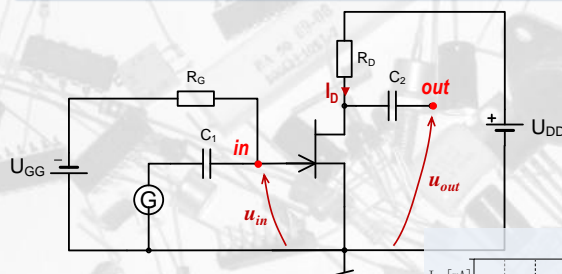
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# JUNCTION FIELD EFFECT TRANSISTOR

## AMPLIFYING DEVICE - GRAPHIC INTERPRETATION



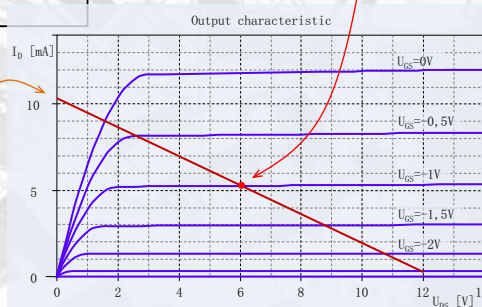
**Operating point of a transistor**  
– it is a point at output characteristic described by coordinates ( $U_{DS}$ ,  $I_D$ )

For output circuit („ring”) we have:

$$U_{DS} + I_D R_D = U_{DD}$$

After transformation ( $I_D = f(U_{DS})$ ):

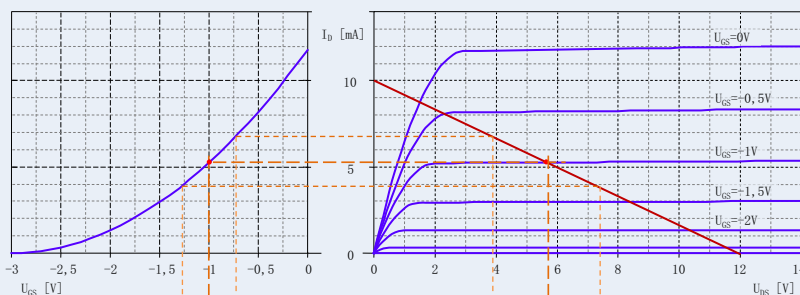
$$I_D = -\frac{1}{R_D} U_{DS} + \frac{U_{DD}}{R_D}$$



# JUNCTION FIELD EFFECT TRANSISTOR

## AMPLIFYING DEVICE - GRAPHIC INTERPRETATION

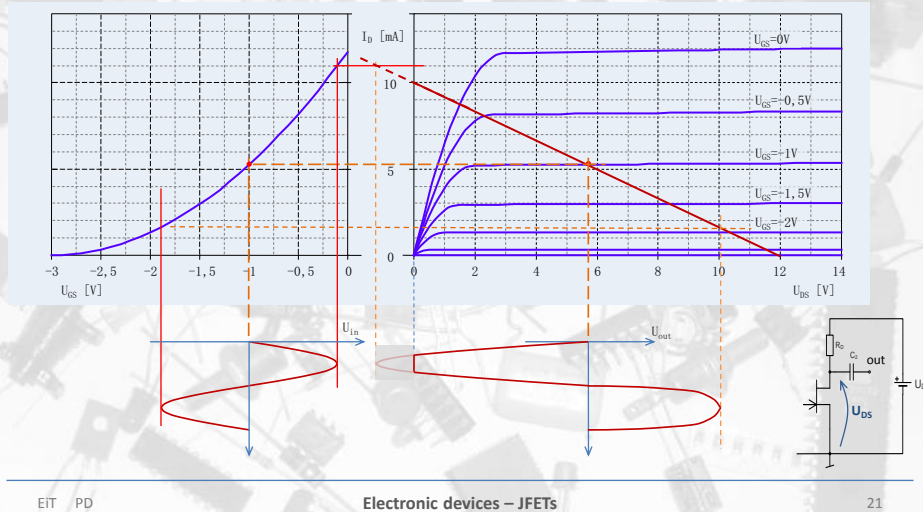
### AMPLIFICATION



# JUNCTION FIELD EFFECT TRANSISTOR

## AMPLIFYING DEVICE - GRAPHIC INTERPRETATION

### DISTORTION



# JUNCTION FIELD EFFECT TRANSISTOR

## AMPLIFYING DEVICE - ANALYTICAL DESCRIPTION

The saturation current is:  $I_D = I_{DSS} \left(1 - \frac{U_{GS}}{U_P}\right)^2$  (for simplification we neglect shortening of the channel) (1)

The total voltage at the gate  $U_{GS}(t)$ :  $u_{GS} = U_{GS} + u_{gs}$  (2)

introducing (2) to (1):  $i_D = I_{DSS} \left(1 - \frac{u_{GS}}{U_P}\right)^2 = I_{DSS} \left(1 - \frac{U_{GS}}{U_P}\right)^2 - 2 \frac{I_{DSS}}{U_P} \left(1 - \frac{U_{GS}}{U_P}\right) u_{gs} + I_{DSS} \frac{u_{gs}^2}{U_P^2}$  (3)

DC  $I_D$  component      small-signal  $i_d$  component

For suitably small amplitude of the input voltage  $u_{in}$  we can linearize transistor characteristics. We consider then linear model of transistor and small-signal analysis.

The small-signal condition results from the selection of  $u_{in}$ , in such a way that the second part of small-signal component ( $\sim u_{gs}^2$ ) is negligible (knowing that  $u_{in} = u_{gs}$ ):

$$2 \frac{I_{DSS}}{U_P} \left(1 - \frac{U_{GS}}{U_P}\right) u_{gs} \gg I_{DSS} \frac{u_{gs}^2}{U_P^2} \quad (4)$$

After transformation:  $2(U_P - U_{GS}) \gg u_{gs}$  (5)

$2(U_P - U_{GS}) \gg u_{gs}$

small-signal condition

## JUNCTION FIELD EFFECT TRANSISTOR

### AMPLIFYING DEVICE - ANALYTICAL DESCRIPTION

Therefore, taking into account small-signal condition, the total drain current can be described as **linear** function of  $u_{gs}$ :

$$i_D = I_D - 2 \frac{I_{DSS}}{U_P} \left( 1 - \frac{U_{GS}}{U_P} \right) u_{gs} \quad (6)$$

Small-signal condition allows us „to get rid off“ component that is proportional to  $u_{gs}^2$ . There only remains component proportional to  $u_{gs}$  – therefore it is right to talk about linearization of characteristics and the linear model of the transistor.

If we denote the proportionality factor in front of  $u_{gs}$  in (6) as  $g_m$ , then the drain current is:

$$i_D = I_D - g_m u_{gs} \quad (7)$$

Coefficient  $g_m$  is expressed in [A/V] and it depends on the operation point as well as physical properties represented by  $U_P$  and  $I_{DSS}$ .

$$g_m = -2 \frac{I_{DSS}}{U_P} \left( 1 - \frac{U_{GS}}{U_P} \right) \quad (8)$$

Parameter  $g_m$  is called **transconductance**:

We considered transconductance for saturation range, the conditions the transistor works in as an amplifier. The reader will examine the case of the transistor operating in the linear range using the given definition of the transconductance.

## JUNCTION FIELD EFFECT TRANSISTOR

### SMALL-SIGNAL PARAMETERS, PART 1

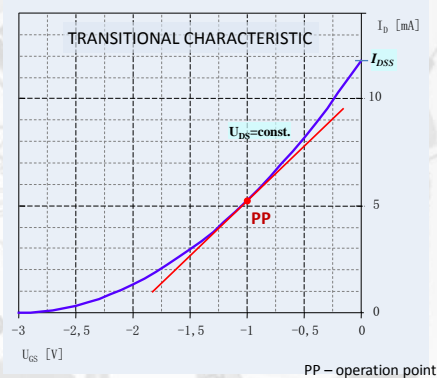
**Transconductance (def.):**

$$g_m = \left. \frac{\partial I_D}{\partial U_{GS}} \right|_{U_{DS} = \text{const.}} \quad [\text{A/V}]$$

### Graphical interpretation

The slope of the tangent to the transitional characteristic of the transistor at the operation point.

Transconductance describes the amplifying properties of the transistor

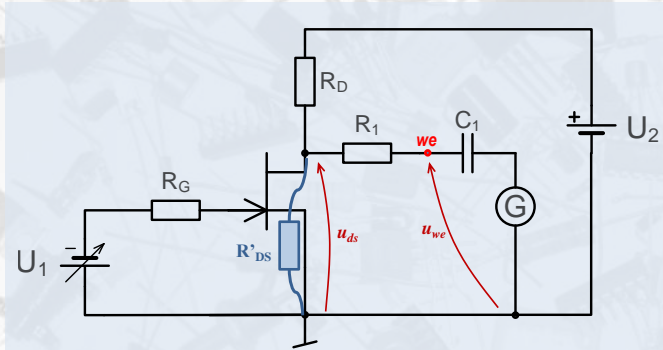


PP – operation point

# JUNCTION FIELD EFFECT TRANSISTOR

## CONTROLLED RESISTOR

controlled voltage divider of alternating signals



divider:

$$u_{ds} = u_{gs} \frac{R'_{DS}}{R'_{DS} + R_1}$$

$$R'_{DS} = R_1 \frac{u_{ds}}{u_{gs} - u_{ds}}$$

only for  $R_D \gg R'_{DS}$

Whether:

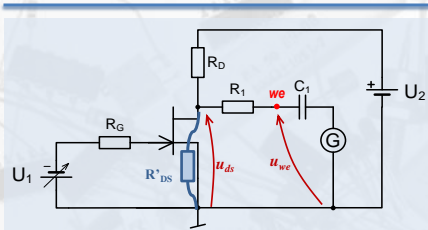
$$R'_{DS} = R_{DS} ?$$

or:

$$R'_{DS} = r_{ds} ?$$

# JUNCTION FIELD EFFECT TRANSISTOR

## CONTROLLED RESISTOR



Resistance:

- static

$$R_{DS} = \frac{U_{DS}}{I_{DS}}$$

- dynamic

$$r_{ds} = \frac{u_{ds}}{i_{ds}}$$

or (from def.):

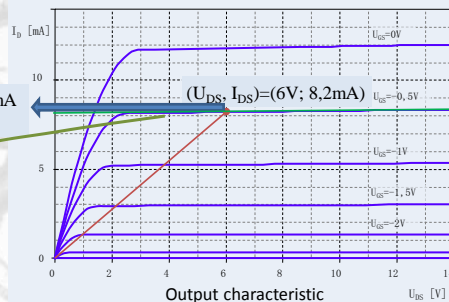
$$r_{ds} = \frac{\partial U_{DS}}{\partial I_{DS}} \equiv \frac{\Delta U_{DS}}{\Delta I_{DS}}$$

$$R_{DS} = 6V/8,2mA$$

$$R_{DS} = 731\Omega$$

very small slope

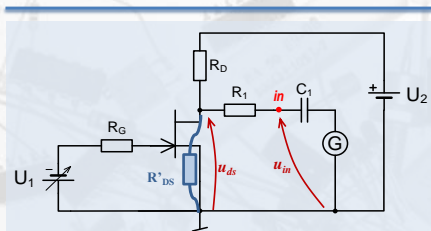
$r_{ds}$  – very large



Output characteristic

# JUNCTION FIELD EFFECT TRANSISTOR

## CONTROLLED RESISTOR



Resistance:

- static

$$R_{DS} = \frac{U_{DS}}{I_{DS}}$$

- dynamic

$$r_{ds} = \frac{u_{ds}}{i_{ds}}$$

or:

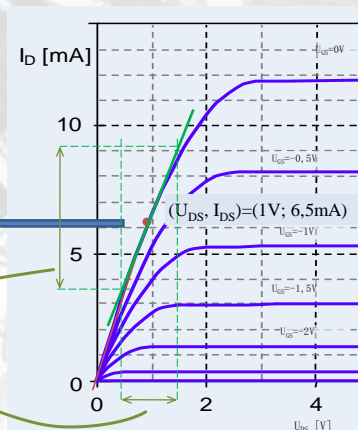
$$r_{ds} = \frac{\Delta U_{DS}}{\Delta I_{DS}} = \frac{\partial U_{DS}}{\partial I_{DS}}$$

$$R_{DS} = 1\text{V}/6,5\text{mA}$$

$$R_{DS} = 154\Omega$$

$$r_{ds} = 1\text{V}/5,5\text{mA}$$

$$r_{ds} = 181\Omega$$



In linear area:  $R'_{DS} \approx R_{DS}$

In saturation area:  $R'_{DS} = r_{ds}$

: JFET – controlled resistance

: JFET - amplifier

# JUNCTION FIELD EFFECT TRANSISTOR

## SMALL-SIGNAL PARAMETERS, PART 2

- Transconductance
- Output (drain) conductance

def. 
$$g_{ds} = \frac{\partial I_D}{\partial U_{DS}} \Big|_{U_{GS}=\text{const.}}$$

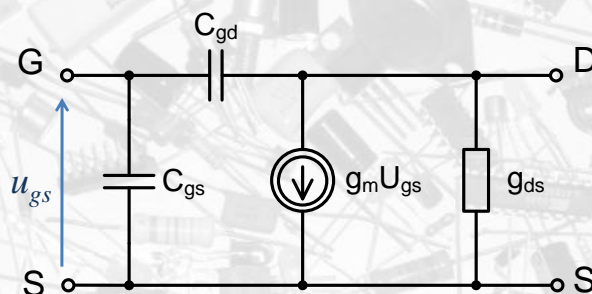
- Series resistances of drain and source ( $r_{dd}$  i  $r_{ss}$ )  
(very often they are negligible)
- Capacitance gate-drain  $C_{gd}$  and gate-source  $C_{gs}$

REMARK: conductances are described by different relations and they have different values in linear as well as in saturation areas.



# JUNCTION FIELD EFFECT TRANSISTOR

## SMALL-SIGNAL EQUIVALENT CIRCUIT



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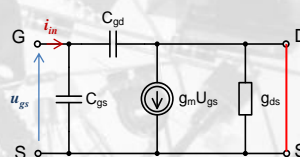
# JUNCTION FIELD EFFECT TRANSISTOR

## FREQUENCY LIMITS



### Cut-off frequency $f_T$

This is the frequency at which the input current is equal to the controlled current source from small-signal model, provided that the output terminals are shorted.



At shorted output terminals, the input current:  $i_{in} = j\omega(C_{gs} + C_{gd})u_{gs}$

At cut-off frequency  $f_T$  absolute value of input current has to be equal to the absolute value of controlled current source, therefore:

$$|i_{in}| = \omega_T (C_{gs} + C_{gd}) U_{gs} = g_m U_{gs}$$

$$2\pi f_T (C_{gs} + C_{gd}) U_{gs} = g_m U_{gs}$$

Finally:

$$f_T = \frac{g_m}{2\pi(C_{gs} + C_{gd})}$$

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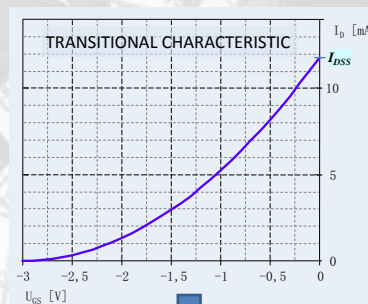
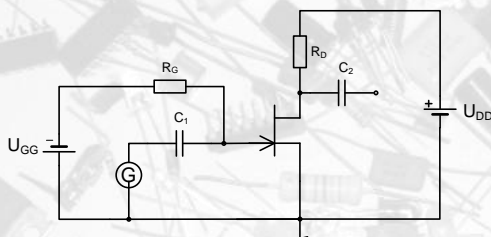
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# JUNCTION FIELD EFFECT TRANSISTOR

## WHAT IS THE PURPOSE OF SMALL-SIGNAL MODELING?

### Example:

Calculate the voltage gain for the circuit shown below, if  $U_{DD}=10V$ ,  $R_D=1k\Omega$ ,  $U_{GG}=1V$ .



$$I_{DSS} = 12\text{mA}$$

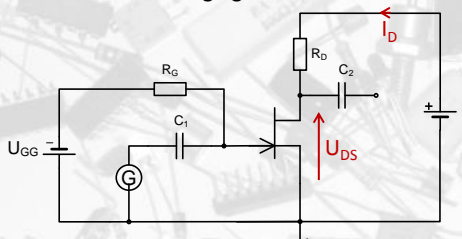
$$U_p = -3V$$

# JUNCTION FIELD EFFECT TRANSISTOR

## WHAT IS THE PURPOSE OF SMALL-SIGNAL MODELING?

### Example:

Calculate the voltage gain for the circuit shown below, if  $U_{DD}=10V$ ,  $R_D=1k\Omega$ ,  $U_{GG}=1V$ .



Is the transistor working in the saturation area?

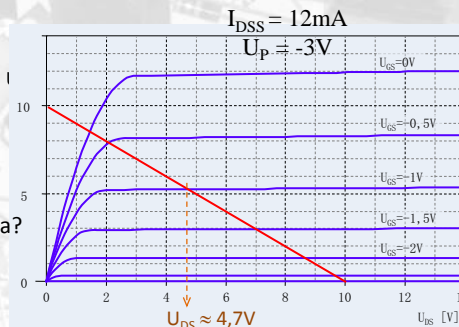
$$U_{DS} > U_{GS} - U_p$$

Equation for the output circuit:

$$U_{DS} + I_D R_D = U_{DD}$$

after transformation:  $I_D = -\frac{1}{R_D} U_{DS} + \frac{U_{DD}}{R_D}$

and after introduction data:  $I_D = -1 \cdot U_{DS} + 10 \text{ [mA]}$



For the given data, if:  $U_{DS} > (-1V) - (-3V)$ , ( $U_{DS} > 2$ ), then transistor works in saturation.

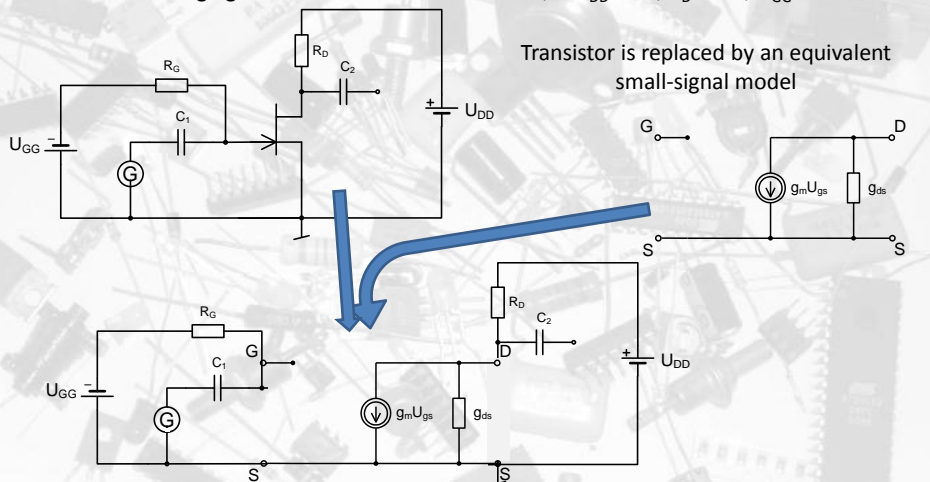
This condition is fulfilled – transistor works in saturation

# JUNCTION FIELD EFFECT TRANSISTOR

## WHAT IS THE PURPOSE OF SMALL-SIGNAL MODELING?

### Example:

Calculate the voltage gain for the circuit shown below, if  $U_{DD}=10V$ ,  $R_D=1k\Omega$ ,  $U_{GG}=1V$ .



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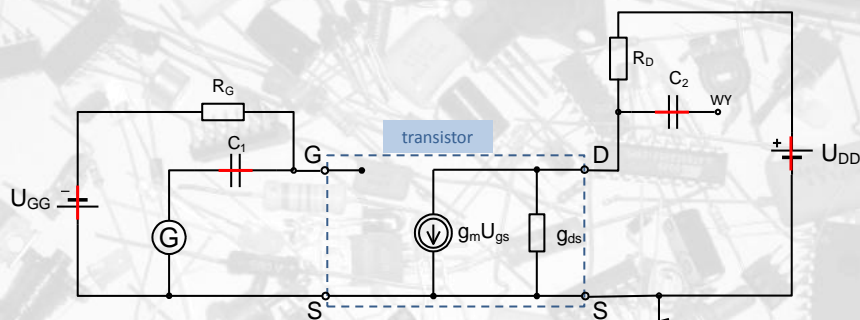
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# JUNCTION FIELD EFFECT TRANSISTOR

## WHAT IS THE PURPOSE OF SMALL-SIGNAL MODELING?

### Example:

Calculate the voltage gain for the circuit shown below, if  $U_{DD}=10V$ ,  $R_D=1k\Omega$ ,  $U_{GG}=1V$ .



for alternating signals we can make short-circuits across capacitors and DC voltage sources ( $R_{in} = 0$ )

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# JUNCTION FIELD EFFECT TRANSISTOR



## WHAT IS THE PURPOSE OF SMALL-SIGNAL MODELING?

**Example:**

Calculate the voltage gain for the circuit shown below, if  $U_{DD}=10V$ ,  $R_D=1k\Omega$ ,  $U_{GS}=1V$ .

After removing unnecessary elements:

